Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/538,324	GUEUGNEAUD, JEAN-MARC
Examiner	Art Unit
Hau V. Phan	3618

	SEARCHED				
Class	Subclass	Date	Examiner		
280	279	2/28/2007	НР		
	276				
	288.4				
403	104	2/28/2007	HP		
	7				
	297				

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
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